

## **C1210C101KCRACTU**

Aliases (C1210C101KCRAC7800) SMD Comm X7R HV, Ceramic, 100 pF, 10%, 500 VDC, X7R, SMD, MLCC, High Voltage, Temperature Stable, 1210, 1.5 mm



General Information		
Series	SMD Comm X7R HV	
Style	SMD Chip	
Description	SMD, MLCC, High Voltage, Temperature Stable	
Features	High Voltage	
RoHS	Yes	
Termination	Tin	
Marking	No	
AEC-Q200	No	
Typical Component Weight	85 mg	
Shelf Life	78 Weeks	
MSL	1	

Dimensions	
Chip Size	1210
L	3.2mm +/-0.2mm
W	2.5mm +/-0.2mm
Т	1.7mm +/-0.20mm
S	1.5mm MIN
В	0.5mm +/-0.25mm

W	2.5mm +/-0.2mm
Т	1.7mm +/-0.20mm
S	1.5mm MIN
В	0.5mm +/-0.25mm
Packaging Specifications	

Specifications		
Capacitance	100 pF	
Measurement Condition	1 kHz 1.0Vrms	
Tolerance	10%	
Voltage DC	500 VDC	
Dielectric Withstanding Voltage	750 VDC	
Temperature Range	-55/+125°C	
Temp. Coefficient	X7R	
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	15%, 1kHz 1.0Vrms	
Dissipation Factor	2.5% 1 kHz 1.0Vrms	
Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours	
Insulation Resistance	100 GOhms	

		Temp. Coefficient	X7R
Packaging Specifications  Packaging T&R, 180mm, Plastic Tape		Capacitance Change with Reference to +25°C and 0 VDC	15%, 1kHz 1.0Vrms
Packaging Quantity	2000	Applied (TCC)	
Packaging Quantity 2000	2000	Dissipation Factor	2.5% 1 kHz 1.0Vrms
		Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours
		Insulation Resistance	100 GOhms

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